

Application/Control No.	Applicant(s)/Patent under Reexamination
10/717,464	SAINT ETIENNE ET AL.
Examiner	Art Unit

2616

Feben M. Haile

SEARCHED				
Class	Subclass	Date	Examiner	
370	235	4/26/2007	FH	
370	217	4/26/2007	FH	
370	223	4/26/2007	FH	
370	278	4/26/2007	FH	
370	392	4/26/2007	FH	
370	252	4/26/2007	FH	
370	399	4/26/2007	FH	
370	394	4/26/2007	FH	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SEARCH	SIRAIEGY	)
	DATE	EXMR
Search: duplex, Ethernet, switch, outer, virtual, logical, sequence, passband, packet, gap, time, CRC	4/26/2007	FH
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